

<b>Notice of References Cited</b>	Application/Control No. 10/668,041	Applicant(s)/Patent Under Reexamination PANEK ET AL.	
	Examiner Rip A. Lee	Art Unit 1713	Page 1 of 1


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	N	JP 56-005842 A	01-1981	Japan	Nakazawa et al.	C08L 23/12
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**NON-PATENT DOCUMENTS**

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	U	JP 56-005842 (English abstract)
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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